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(12) **United States Design Patent**
Wang

(10) **Patent No.:** **US D843,242 S**

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(54) **INFRARED THERMOMETER**

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(72) Inventor: **Kai Wang**, Shenzhen (CN)

(**) Term: **15 Years**

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(51) **LOC (11) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/57**

(58) **Field of Classification Search**
USPC D10/57, 58
CPC G01J 5/04; G01J 5/041; G01J 5/042; G01J 5/043; G01J 5/044; G01J 5/045; G01J 5/046; G01J 5/047; G01J 5/048; G01J 5/049; G01J 5/0265; G01K 1/02; G01K 1/022; G01K 1/024; G01K 1/08; G01K 1/083; G01K 1/086; G01K 3/00-3/14; G01K 203/145; G01K 13/002; G01K 13/004; G01K 2219/00; G01K 5/04-5/225; G01K 5/22; G01K 221/00
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

5,991,700 A * 11/1999 Clay G01J 5/02
374/163
6,179,785 B1 * 1/2001 Martinosky G01J 5/02
374/E13.003

6,192,268 B1 * 2/2001 Yamamoto G01J 5/02
374/121
D676,770 S * 2/2013 Lacotta D10/57
D693,247 S * 11/2013 Juhng D10/57
8,651,736 B2 * 2/2014 Mullin G01J 5/021
374/158
9,885,617 B2 * 2/2018 Tsuchida G01K 7/427

* cited by examiner

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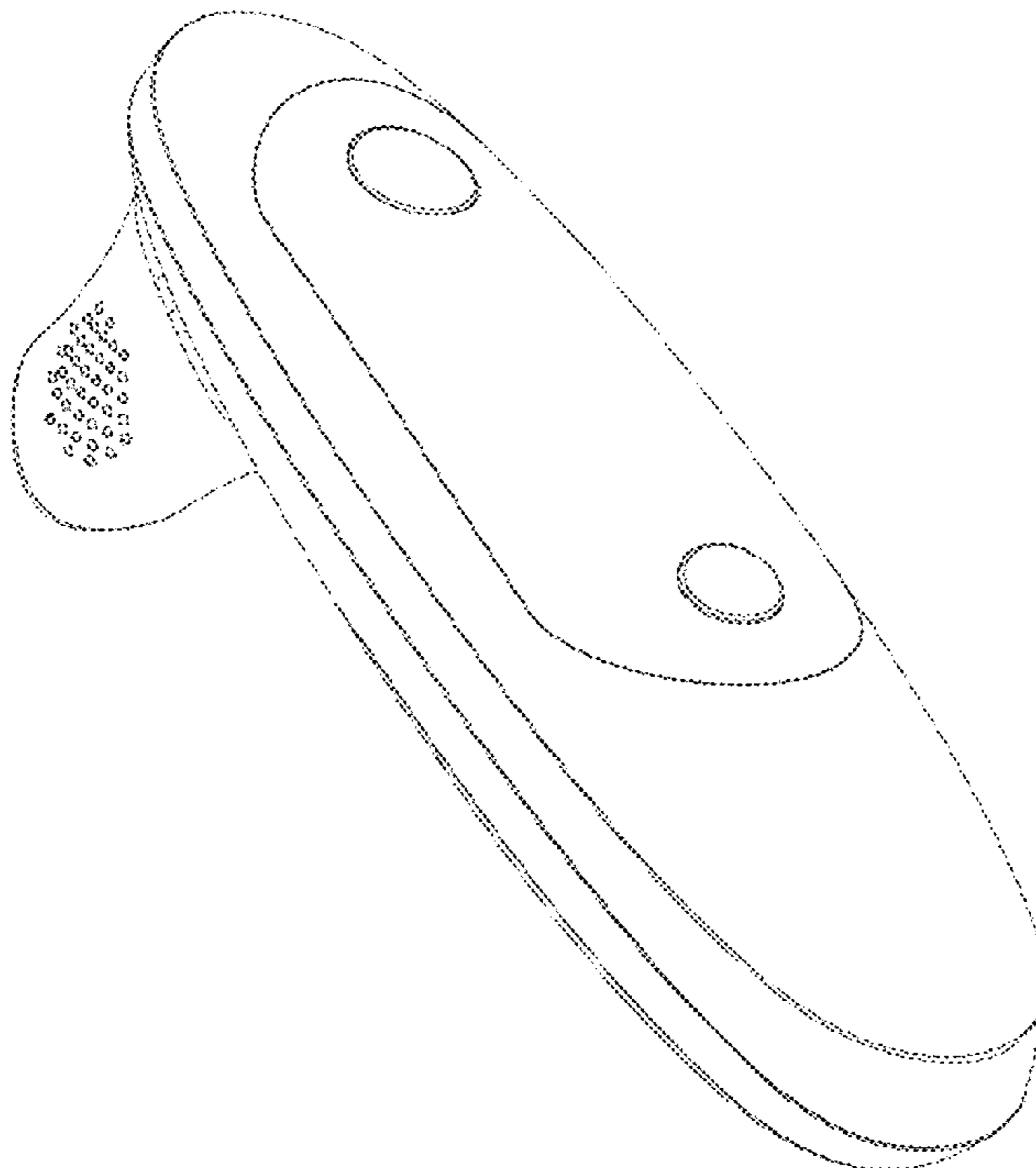
(57) **CLAIM**

The ornamental design for an infrared thermometer, as shown and described.

DESCRIPTION

FIG. 1 is a back perspective view of the infrared thermometer showing my new design;
FIG. 2 is a front view thereof;
FIG. 3 is a back view thereof;
FIG. 4 is a side view thereof;
FIG. 5 is a top view thereof; and,
FIG. 6 is a bottom view thereof.

1 Claim, 5 Drawing Sheets



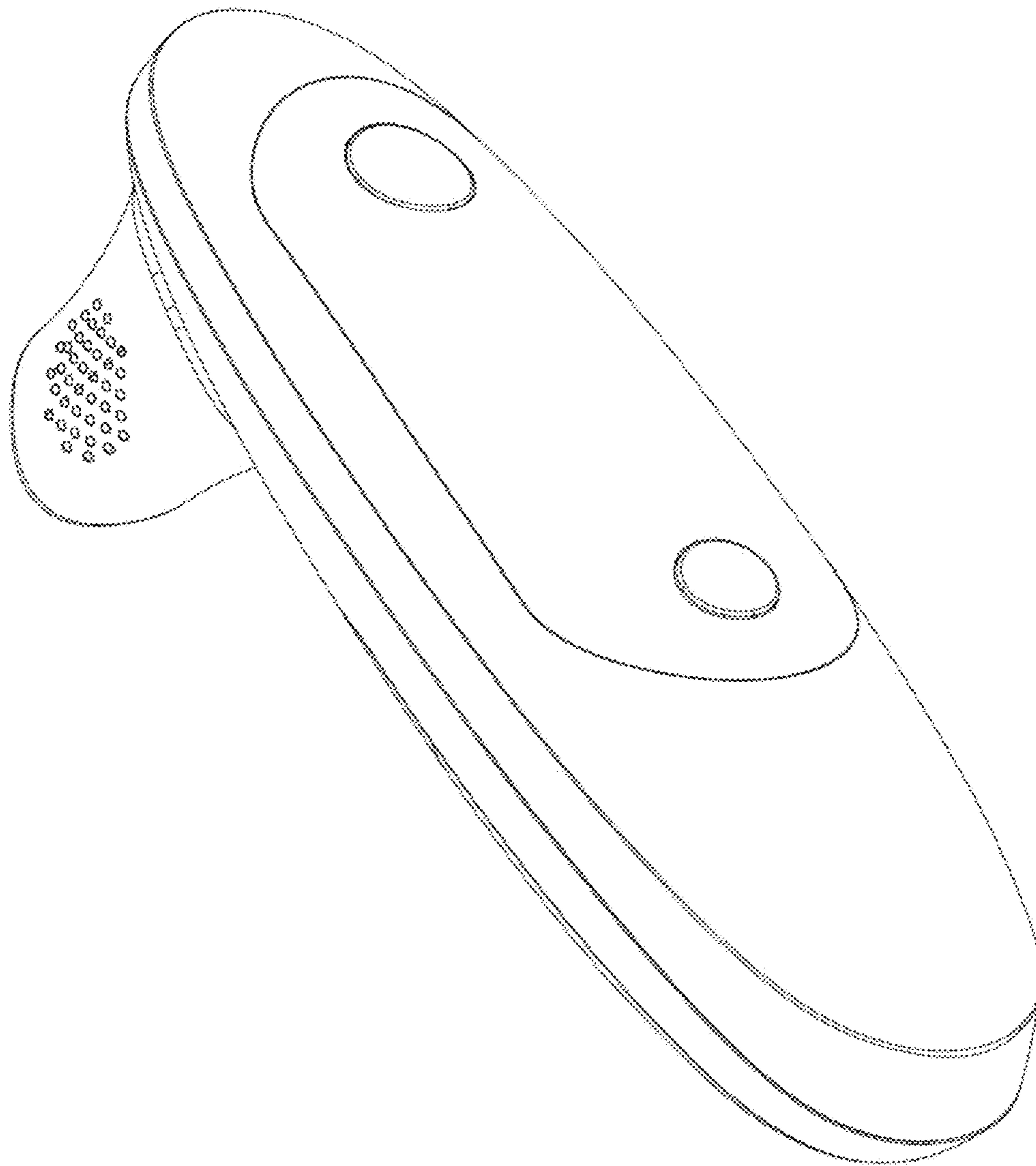


FIG. 1

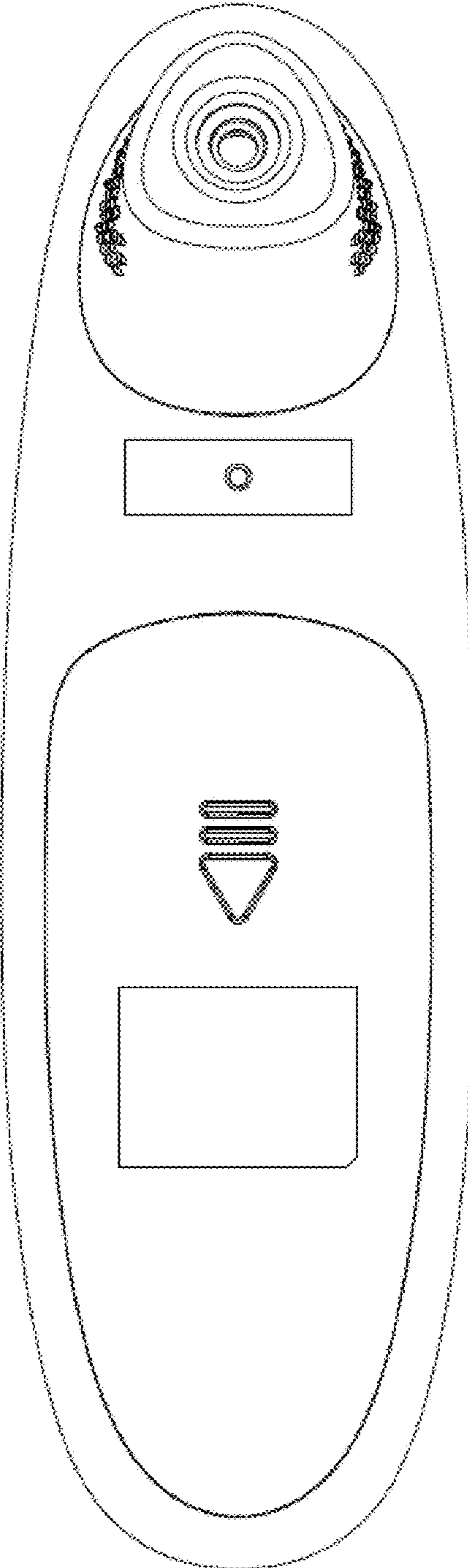


FIG. 2

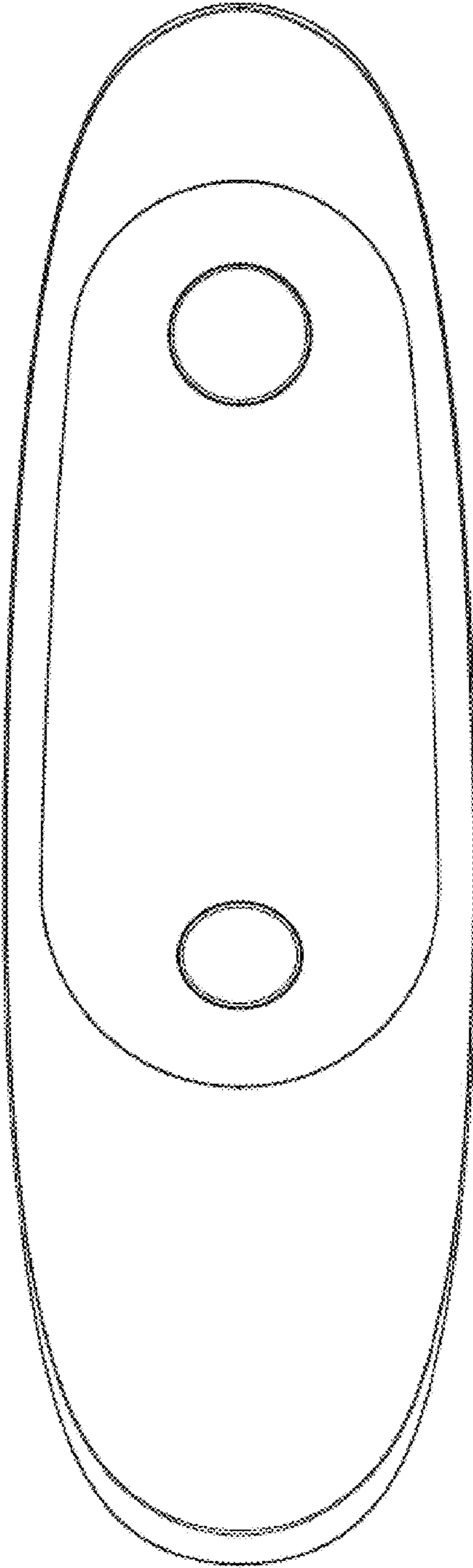


FIG. 3

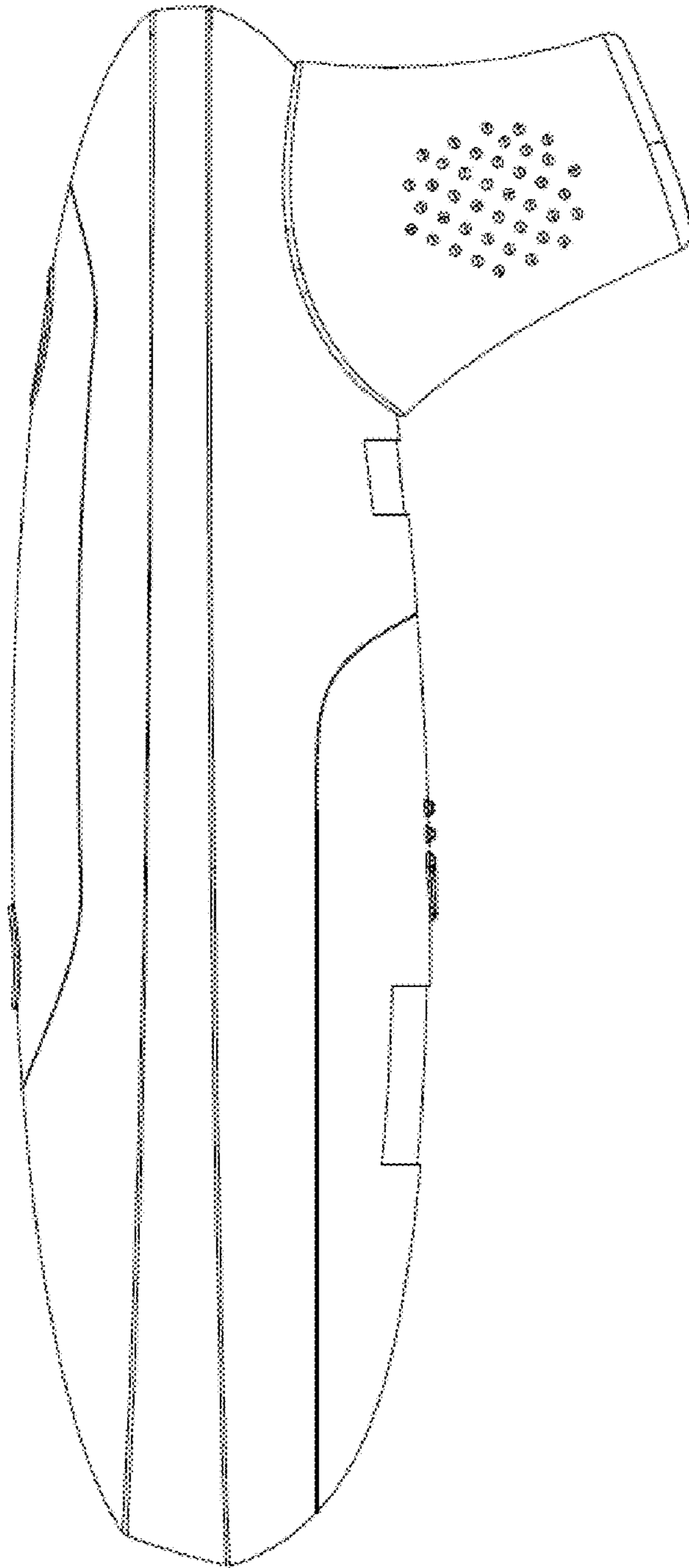


FIG. 4

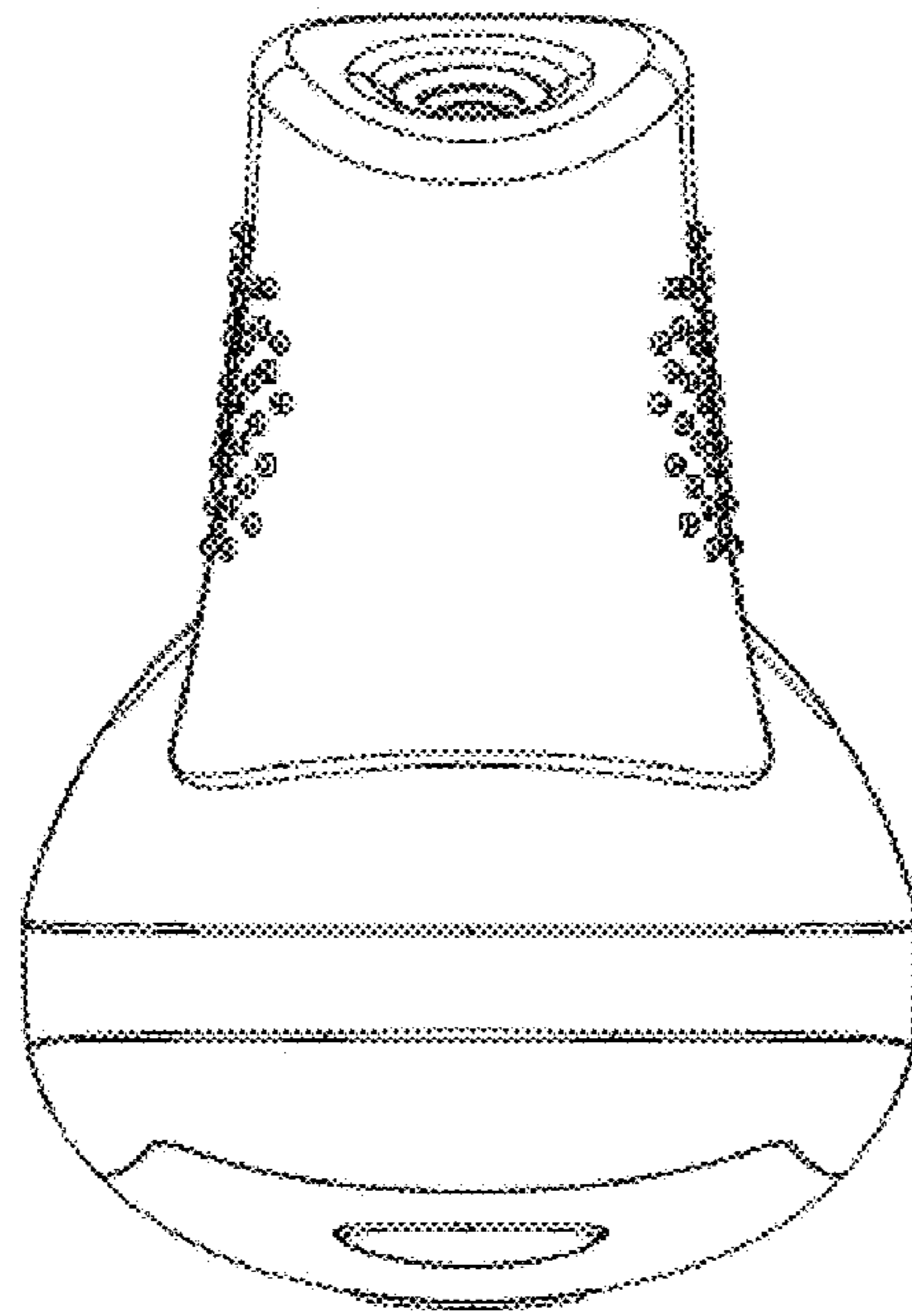


FIG. 5

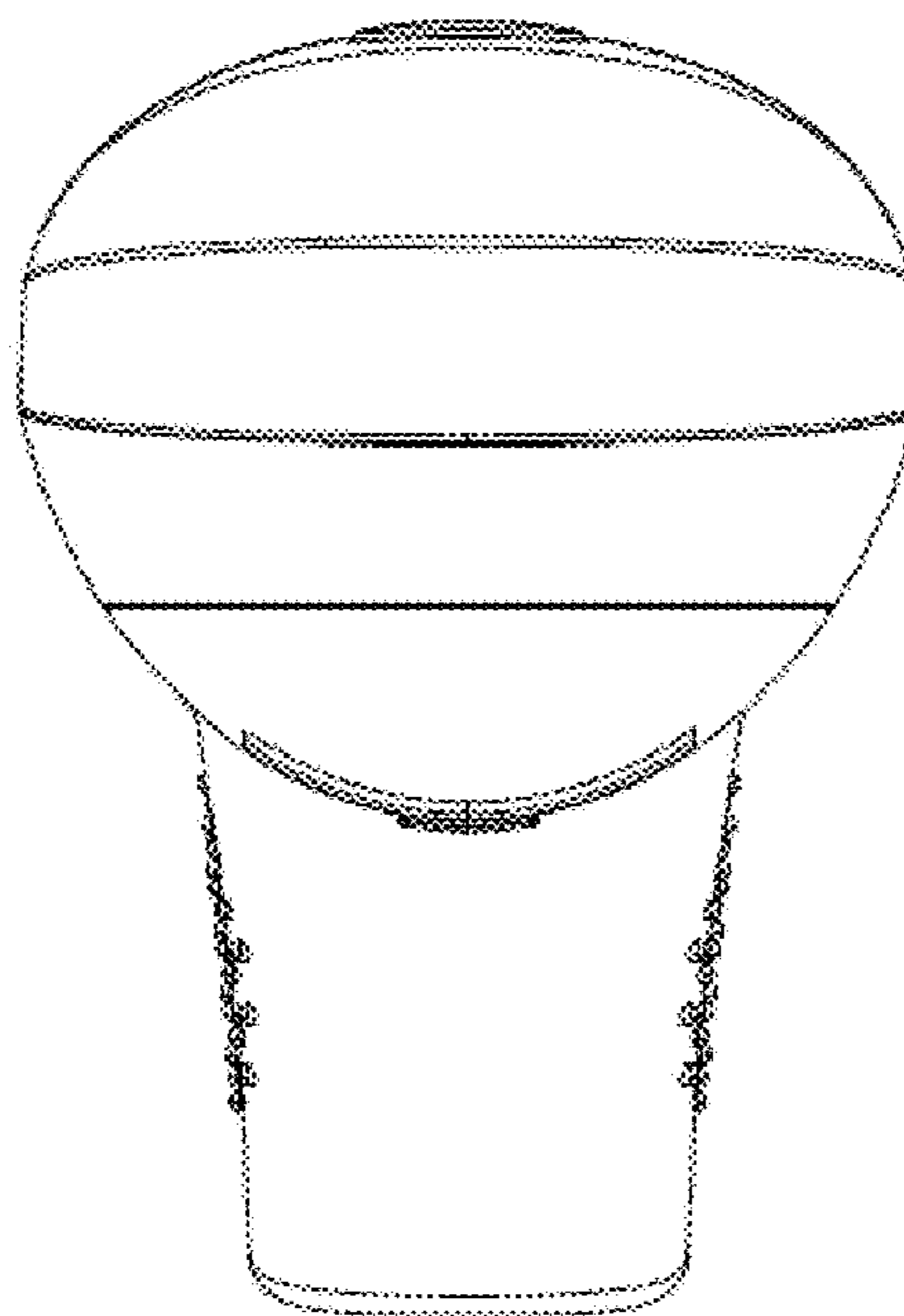


FIG. 6